



# Certificate of Analysis

## IARM 8G

AISI 347 / UNS S34700

### Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

<b>Al</b>	<b>0.0030 ± 0.0006</b>	<b>B</b>	<b>0.0005 ± 0.0003</b>	<b>C</b>	<b>0.042 ± 0.001</b>	<b>Co</b>	<b>0.162 ± 0.004</b>
<b>Cr</b>	<b>17.20 ± 0.03</b>	<b>Cu</b>	<b>0.390 ± 0.005</b>	<b>Mn</b>	<b>1.468 ± 0.009</b>	<b>Mo</b>	<b>0.359 ± 0.005</b>
<b>N</b>	<b>0.046 ± 0.001</b>	<b>Nb</b>	<b>0.53 ± 0.01</b>	<b>Ni</b>	<b>9.02 ± 0.03</b>	<b>O</b>	<b>0.003 ± 0.001</b>
<b>P</b>	<b>0.0327 ± 0.0006</b>	<b>S</b>	<b>0.0126 ± 0.0006</b>	<b>Se</b>	<b>0.01 ± 0.01</b>	<b>Si</b>	<b>0.36 ± 0.01</b>
<b>Sn</b>	<b>0.0107 ± 0.0007</b>	<b>Ta</b>	<b>0.004 ± 0.002</b>	<b>Ti</b>	<b>0.0024 ± 0.0008</b>	<b>V</b>	<b>0.062 ± 0.002</b>
<b>W</b>	<b>0.032 ± 0.002</b>	<b>Zr</b>	<b>0.002 ± 0.002</b>				

Indicative Values listed in ppm

As (70)	Ca (5)	Mg (<200)	Pb (<200)	Sb (<200)	Zn (<50)
---------	--------	-----------	-----------	-----------	----------

#### Description and Intended Use

This CRM may come in the form of a solid disc or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

#### Interpretation of Data

1. Certified values listed reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community, and are reported as wt% unless otherwise noted.
2. This material was tested using both the solid disks and chips prepared from individual sections of bar. The certified values are considered representative of the overall average composition of the material.
3. Any data reported and enclosed by a parentheses ( ) is a "best estimate" and is not certified. This data could not be quantified sufficiently for certification. It was, however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
4. "Provisional Certificate of Analysis" reports values that support a fully certified reference material; it also indicates that values may be in a continued process of statistical evaluation and are subject to change.
5. Chips are not certified for Oxygen analysis.



The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material.

	Al	As	B	C	Ca	Co	Cr	Cu	Mg	Mn	Mo	N	Nb	Ni	O	P
1	0.001	0.0039	0.00024	0.0396	0.00036	0.147	17.093	0.378	0.0002	1.444	0.345	0.0414	0.507	8.897	0.0019	0.0302
2	0.0023	0.006	0.0004	0.0396	0.0004	0.154	17.155	0.378	0.0007	1.449	0.35	0.04355	0.5074	8.954	0.002	0.0317
3	0.0024	0.008	0.0004	0.04	0.0004	0.158	17.159	0.381	0.02	1.45	0.3506	0.045	0.516	8.966	0.0023	0.0318
4	0.0024	0.0084	0.0004	0.04	0.0004	0.1597	17.17	0.382		1.455	0.3515	0.0452	0.516	8.99	0.0024	0.032
5	0.0026	0.0089	0.0004	0.04015	0.0007	0.1598	17.172	0.384		1.4555	0.353	0.0453	0.5229	8.991	0.0026	0.032
6	0.0027		0.0005	0.0409		0.1616	17.19	0.3843		1.457	0.357	0.0456	0.523	9.01	0.0027	0.0321
7	0.0029		0.0006	0.041		0.162	17.2035	0.385		1.4645	0.3573	0.0456	0.5301	9.014	0.004	0.0323
8	0.003		0.0013	0.041		0.162	17.21	0.3925		1.47	0.359	0.046	0.532	9.038	0.00549	0.0329
9	0.003			0.0428		0.162	17.22	0.3934		1.472	0.359	0.046	0.5334	9.0389	0.0069	0.0329
10	0.0032			0.0432		0.162	17.232	0.3946		1.476	0.3601	0.04622	0.5338	9.044		0.033
11	0.0039			0.0437		0.164	17.2337	0.396		1.4767	0.361	0.0464	0.5347	9.0559		0.033
12	0.0042			0.0441		0.167	17.26	0.3964		1.478	0.367	0.048	0.541	9.06		0.0338
13	0.0049			0.0443		0.1689	17.27	0.399		1.4874	0.37	0.048	0.547	9.0865		0.0339
14				0.046		0.173	17.27	0.40		1.489	0.3711		0.5484	9.11		0.0339
15				0.0468				0.404		1.50	0.3721		0.58			0.035
Mean	0.003	0.007	0.0005	0.042	0.0005	0.162	17.2	0.39	0.01	1.468	0.359	0.046	0.53	9.02	0.003	0.0327
STDV.	0.001	0.002	0.0003	0.002	0.0001	0.006	0.05	0.009	0.01	0.02	0.008	0.002	0.02	0.06	0.002	0.001
<b>Certified</b>	<b>0.0030</b>	<b>(0.007)</b>	<b>0.0005</b>	<b>0.042</b>	<b>(0.0005)</b>	<b>0.162</b>	<b>17.20</b>	<b>0.390</b>	<b>(&lt;0.02)</b>	<b>1.468</b>	<b>0.359</b>	<b>0.046</b>	<b>0.53</b>	<b>9.02</b>	<b>0.003</b>	<b>0.0327</b>
95% C.I.	0.0006		0.0003	0.001		0.004	0.03	0.005		0.009	0.005	0.001	0.01	0.03	0.001	0.0006
Methods	X,O	O,IM,A	O,I	O,C	O,I	X,O,I	X,W,O,I	X,O,I	O,IM	X,O,I	X,O,I	O,F	X,O,I	X,O,I	O,F	X,O,I

	Pb	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr				
1	0.00009	0.011	0.00048	0.00001	0.3135	0.0088	0.001	0.0011	0.0545	0.024	0.0003	0.0001				
2	0.0001	0.0111	0.0022	0.0002	0.329	0.0098	0.0015	0.0012	0.0556	0.029	0.0009	0.0001				
3	0.00056	0.0119	0.0186	0.0015	0.3477	0.01	0.004	0.0012	0.0597	0.0309	0.0039	0.0006				
4	0.0016	0.012	0.019	0.004	0.357	0.01	0.0041	0.0015	0.06	0.031	0.005	0.00062				
5	0.019	0.0121	<0.004	0.0041	0.3573	0.01	0.0042	0.0017	0.0606	0.031	<0.00001	0.002				
6	<0.001	0.0123		0.028	0.362	0.01	0.00489	0.002	0.061	0.0314		0.0035				
7		0.0123			0.367	0.0101	0.007	0.0024	0.061	0.033		0.004				
8		0.0125			0.368	0.011		0.0025	0.0621	0.0333		0.007				
9		0.0125			0.368	0.011		0.0027	0.063	0.0338						
10		0.0129			0.3695	0.0111		0.003	0.0634	0.034						
11		0.013			0.371	0.0116		0.004	0.0637	0.036						
12		0.013			0.372	0.012		0.0051	0.064	0.037						
13		0.0141			0.374	0.012			0.066							
14		0.01525			0.38	0.013			0.067							
15									0.068							
Mean	0.004	0.0126	0.01	0.01	0.36	0.0107	0.004	0.0024	0.062	0.032	0.003	0.002				
STDV.	0.008	0.001	0.01	0.01	0.02	0.001	0.002	0.001	0.004	0.003	0.002	0.002				
<b>Certified</b>	<b>(&lt;0.02)</b>	<b>0.0126</b>	<b>(&lt;0.02)</b>	<b>0.01</b>	<b>0.36</b>	<b>0.0107</b>	<b>0.004</b>	<b>0.0024</b>	<b>0.062</b>	<b>0.032</b>	<b>(&lt;0.005)</b>	<b>0.002</b>				
95% C.I.	0.0006			0.01	0.01	0.0007	0.002	0.0008	0.002	0.002		0.002				
Methods	O,IM,A	O,C	O,IM,A	O,IM,I,A	X,O,I	X,O,I,A	X,O,I	X,O,I	X,O,I	X,O,I	O,IM,A	X,O,IM,I				

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

## Participating Laboratories

Certified Alloy Products, Inc.  
SPECTRO Analytical Instruments Inc.  
AADFW, Inc.  
Ellwood National Steel  
PM Kalco, Inc  
Crucible Industries  
Element - Huntington Beach

Long Beach, CA  
Mahwah, NJ  
Eules, TX  
Irvine, PA  
Wheatland, PA  
Syracuse, NY  
Huntington Beach, CA

Element - Huntington Beach  
Laboratory Testing, Inc.  
Laboratorio Prove Materiali S. Marco srl  
Davis Alloys Manufacturing, LLC  
MetalTek International, Inc.  
Exova - Gary  
Laboratory Testing, Inc.

Huntington Beach, CA  
Hatfield, PA  
Schio, Italy  
Sharpville, PA  
Waukesha, WI  
Gary, IN  
Hatfield, PA

## Traceability

Members of the "Inter-Laboratory Analysis Program" (ILAP) validate test methods and instrument performance utilizing SRMs, CRMs, and RMs produced by recognized Certifying Bodies. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are:

ALPHA AR645	ALPHA AR654	ALPHA AR657	ALPHA AR676	ALPHA AR881	ALPHA AR882	ALPHA AR890	ASTM 0441	ASTM 442
ASTM 921	ASTM 922	ASTM 9811	ASTM 9831	ASTM 9832	BCS 346	BCS SS475	BS 316A	BS 347
BS 60C	BS 84J	BS347B	IARM 162C	IARM 2C	IARM 347A	IARM 35J	IARM 8B	IARM 8C
IARM 8D	IARM 8E	LECO 501-501	LECO 501-502	LECO 501-675	LECO 502-257	LECO 502-269	MBH 13X12855L	MBH 13X14212Q
MBH 13X18003B	MBH 13X34700	MBH 13X34700A	NIST 348A	NIST 101G	NIST 1172	NIST 160B	NIST 3107	NIST 3109A
NIST 3149	NIST 3155	NIST 3161A	NIST 3162A	NIST 3169	NIST 361	NIST 363	NIST 897	NIST 898
NIST 899								

## Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where  $N_{prod}$  is the number of units produced and  $N_{min}$  is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity is also determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity ( $U_{hom}$ ). Uncertainty of the material is calculated by equation 2, where  $H=U_{hom}$ ,  $S$ = Standard deviation,  $t$ = t-value at 95% CI, and  $n$ = number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}})$$
$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30–1992 list the following:

**Certifying Body:** Any technically competent body (organization or firm, public or private) that issues a reference material certificate with the information detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards or Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

**Reference Material (RM):** Material or substance, with one or more property values that are sufficiently homogeneous and well established, to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

**Certified Reference Material (CRM):** Reference material, accompanied by a certificate, with one or more property values certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

**Inter-Laboratory Analysis Program (ILAP):** ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", but also outlines a well thought out and logical plan for conducting an inter laboratory program involving multiple analytical techniques. Therefore, the guidelines established in ASTM E691-87 were applied to all aspects of this inter laboratory program, including the protocols for planning, handling, analysis and treatment of resulting data.

**Methods of Analysis:** The "Inter Laboratory Analysis Program" analyzes a wide variety of materials, and as a result, no single analytical method would provide optimum analytical results. Therefore, a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, X-Ray spectrometric, and other accepted methods were used to produce analytical data. Carbon, Sulfur, Nitrogen, and Oxygen results were supplied from combustion and OE instrument procedures.

**Expiration of Certification:** The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

**Instructions for Use:** The test surface is on the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. **Chips are not to be used for Oxygen analysis.**

**Selection of Materials:** A "batch" or "series" is defined as a continuous length of bar produced from a single heat. The majority of IARM materials are in wrought condition; other methods of manufacture are utilized if necessary. ILAP samples are removed from equal sections from the total length of the bar. A portion of each section is converted to chips and a thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis.



David Coler, General Manager

Analytical Reference Materials International



Analytical Reference Materials International • 276 Abby Road • Manchester, NH 03103  
Telephone (603) 935-4100 • Fax (603) 935-4101 • www.ARMInternational.com • ARMI@LGCgroup.com



8G-01001900-IARM-F

10/4/2017 3 / 3